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Application/C	Control No.	Applica Reexam	nt(s)/Patent un nination	ider
10/767,373		TAKAY	A ET AL.	
Examiner		Art Unit		
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SEARCHED			
Class	Subclass	Date	Examiner
336	65, 83, 200, 232	12/27/2005	TTN
257	531	12/27/2005	TTN
aplated		4/11/06	TTN

INTERFERENCE SEARCHED			
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